

## Bettersizer S3 Plus in particle size and particle shape analysis - Now with improved dual camera system

For particle characterization, the Bettersizer S3 Plus combines laser diffraction and dynamic image analysis in one instrument.



Bettersizer S3 Plus optionally equipped with the autosampler BT-A60

The combination of both technologies enable a new level of particle size and particle shape analysis from 10 nm to 3500 µm:

1. **Patented DLOI (Dual Lenses Oblique Incidence) System:** Laser diffraction, which is designed based on the Fourier structure to guarantee the accurate measurements even of ultrafine particles from 10 nm.
2. **Dual-Camera Imaging System:** Dynamic image analysis, now with improved cameras, enables visualisation of individual particle images for morphological particle information, that is independent of laser diffraction. In addition to particle size, individual shape parameters or the detection of agglomerates, crushed or foreign particles can easily be recorded.
3. **Groundbreaking Combination 2-in-1 System:** Laser Diffraction in combination with Dynamic Image Analysis is used to simultaneously characterize particle size, size distribution, and particle shape over a broad measuring range. Working in tandem, the DLOI system precisely measures particle size down to 10 nm, whereas the dual camera imaging system efficiently detects oversized particles up to 3500 µm and provides shape results.

The advantages of technologies combination in one instrument are obvious from the analysis of widely distributed samples. The Bettersizer S3 Plus camera system can effectively detect statistically underrepresented, oversized particles that are not to detect with standard laser diffraction analysis.

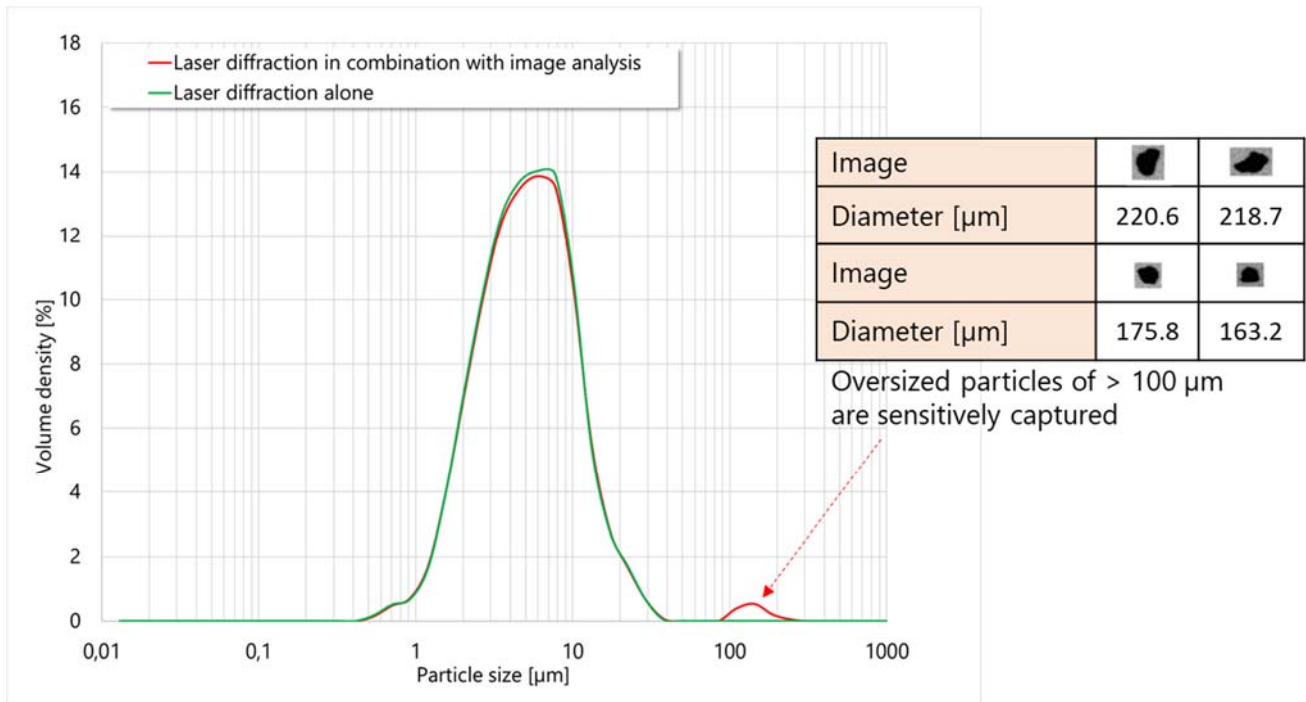


Figure 2: Analysis of a widely distributed sample – Bettersizer S3 Plus laser diffraction and/or dynamic image analysis